

March 2013

FCH35N60

N-Channel SuperFET[®] MOSFET 600 V, 35 A, 98 m Ω

Features

- 650 V @ T_J = 150°C
- Typ.R_{DS(on)} = 79 m Ω
- Ultra Low Gate Charge (Typ. Q_g = 139 nC)
- Low Effective Output Capacitance (Typ. C_{oss}.eff = 340 pF)
- · 100% Avalanche Tested

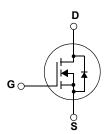
Application

- · Solar Inverter
- AC-DC Power Supply

Description

SuperFET® MOSFET is Fairchild Semiconductor® s first generation of high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET MOSFET is very suitable for the switching power applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications.





MOSFET Maximum Ratings T_C = 25°C unless otherwise noted*

Symbol		Parameter		FCH35N60	Unit
V _{DSS}	Drain to Source Voltage			600	V
V _{GSS}	Gate-Soure voltage			±30	V
	Drain Current	-Continuous (T _C = 25°C)		35	А
ID	Diamounem	-Continuous (T _C = 100°C)		22.2	A
I _{DM}	Drain Current	- Pulsed	(Note 1)	105	Α
E _{AS}	Single Pulsed Avalanche E	nergy	(Note 2)	1455	mJ
I _{AR}	Avalanche Current		(Note 1)	35	Α
E _{AR}	Repetitive Avalanche Energy		(Note 1)	31.25	mJ
dv/dt	Peak Diode Recovery dv/d	t	(Note 3)	20	V/ns
D	Dower Dissination	(T _C = 25°C)		312.5	W
P_{D}	Power Dissipation	- Derate above 25°C		2.5	W/°C
T _J , T _{STG}	Operating and Storage Ter	nperature Range		-55 to +150	°C
T _L	Maximum Lead Temperature for Soldering Purpose, 1/8" from Case for 5 Seconds			300	°C

*Drain current limited by maximum junction temperature

Thermal Characteristics

Symbol	Parameter		Max.	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case	-	0.4	
$R_{\theta CS}$	Thermal Resistance, Case-to-Heat Sink	0.24	-	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	ı	42	

Package Marking and Ordering Information T_C = 25°C unless otherwise noted

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FCH35N60	FCH35N60	TO-247	-	-	30

Electrical Characteristics

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
D\/	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 25^{\circ} C$	600	-	-	V
BV_{DSS}	Dialii to Source Breakdown voltage	$I_D = 250 \mu A, V_{GS} = 0 V, T_J = 150^{\circ} C$	-	650	-	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C	-	0.6	-	V/°C
BV _{DS}	Drain-Source Avalanche Breakdown Voltage	V _{GS} = 0 V, I _D = 16 A	-	700	-	V
ı	Zoro Cata Valtaga Drain Current	V _{DS} = 600 V, V _{GS} = 0 V	-	-	1	
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 480 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	-	10	μΑ
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

On Characteristics

V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	3.0	-	5.0	V
R _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 17.5 \text{ A}$	-	0.079	0.098	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 17.5 A	-	28.8	-	S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 05 V V 0 V	-	4990	6640	pF
C _{oss}	Output Capacitance	V _{DS} = 25 V, V _{GS} = 0 V — f = 1 MHz	-	2380	3170	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1/11/12	-	140	-	pF
C _{oss}	Output Capacitance	V _{DS} = 480 V, V _{GS} = 0 V, f = 1.0 MHz	-	113	-	pF
Coss eff.	Effective Output Capacitance	V _{DS} = 0 V to 480 V, V _{GS} = 0 V		340	-	pF
Qg	Total Gate Charge at 10V		-	139	181	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DS} = 480 \text{ V}, I_{D} = 35 \text{ A}$	-	31	-	nC
Q_{gd}	Gate to Drain "Miller" Charge	V _{GS} = 10 V (Note 4)	-	69	-	nC
ESR	Equivalent Series Resistance (G-S)	Drain Open, F= 1 MHZ	-	1.4	-	Ω

Switching Characteristics

$t_{d(on)}$	Turn-On Delay Time			-	34	78	ns
t _r	Turn-On Rise Time	V _{DD} = 300 V, I _D = 35 A		-	120	250	ns
t _{d(off)}	Turn-Off Delay Time	$R_G = 4.7 \Omega$		-	105	220	ns
t _f	Turn-Off Fall Time	(Note	e 4)	-	73	155	ns

Drain-Source Diode Characteristics

I _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	35	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	105	Α
V _{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 35 A	-	-	1.4	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 35 A	-	614	-	ns
Q _{rr}	Reverse Recovery Charge	$dI_F/dt = 100 A/\mu s$	-	16.3	-	μС

- $\label{eq:Notes:Notes:} \begin{tabular}{ll} \textbf{Notes:} \\ 1: & \textbf{Repetitive Rating: Pulse width limited by maximum junction temperature} \\ 2: & \textbf{I}_{AS} = 17.5 \ \text{A, } V_{DD} = 50 \ \text{V, } R_G = 25 \ \Omega, \ \text{Starting } T_J = 25^{\circ} \text{C} \\ 3: & \textbf{I}_{SD} \le 35 \ \text{A, di/dt} \le 200 \ \text{A/µs, } V_{DD} \le BV_{DSS}. \ \text{Starting } T_J = 25^{\circ} \text{C} \\ 4: & \textbf{Essentially Independent of Operating Temperature Typical Characteristics} \\ \end{tabular}$

Typical Performance Characteristics

Figure 1. On-Region Characteristics

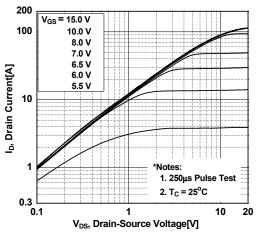


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

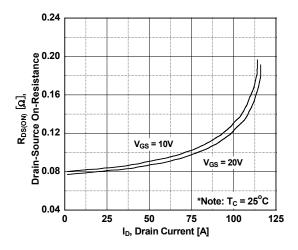


Figure 5. Capacitance Characteristics

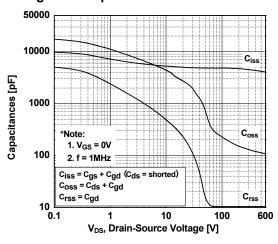


Figure 2. Transfer Characteristics

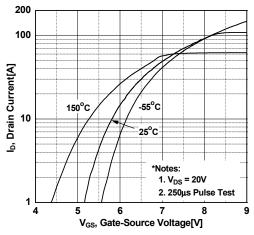


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

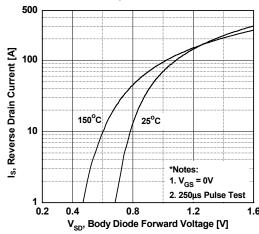
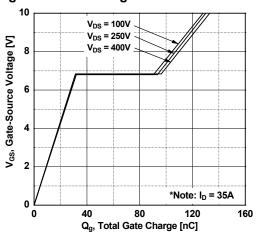


Figure 6. Gate Charge Characteristics



Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

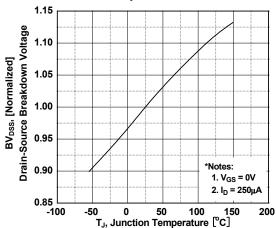


Figure 8. On-Resistance Variation vs. Temperature

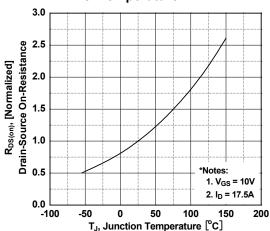


Figure 9. Maximum Safe Operating Area

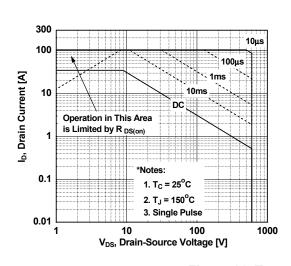


Figure 10. Maximum Drain Current vs. Case Temperature

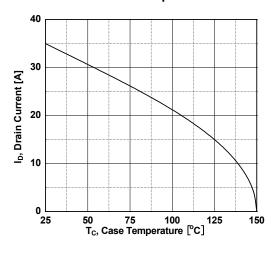
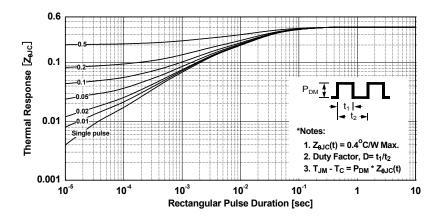
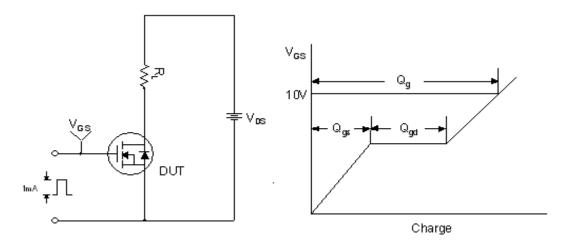


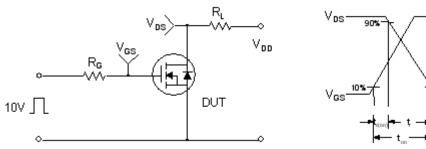
Figure 11. Transient Thermal Response Curve

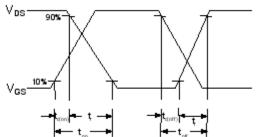


Gate Charge Test Circuit & Waveform

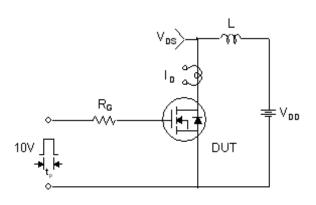


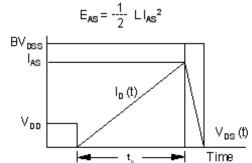
Resistive Switching Test Circuit & Waveforms



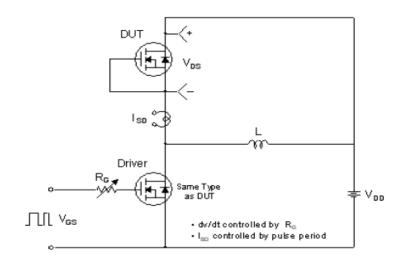


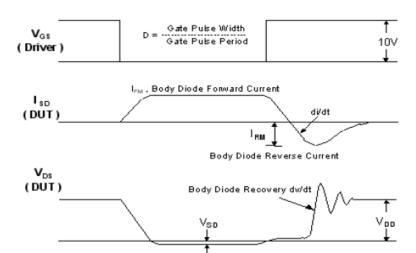
Unclamped Inductive Switching Test Circuit & Waveforms





Peak Diode Recovery dv/dt Test Circuit & Waveforms

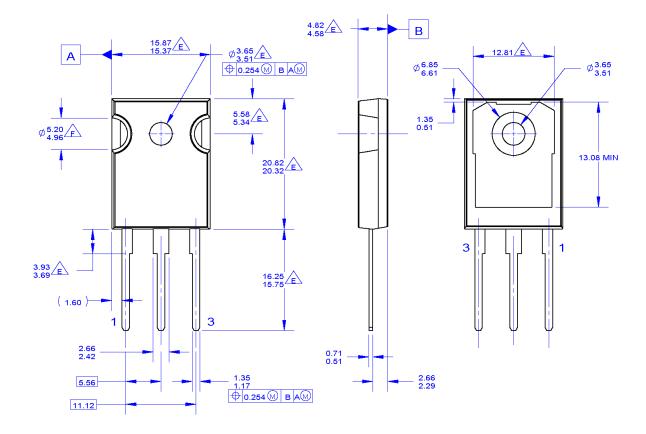




Body Diode Forward Voltage Drop

Mechanical Dimensions

TO-247



NOTES: UNLESS OTHERWISE SPECIFIED.

- PACKAGE REFERENCE: JEDEC TO-247, ISSUE E, VARIATION AB, DATED JUNE, 2004.
 DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS.
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Dimensions in Millimeters





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